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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10026727	12/27/2001	366		2877	

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**CONTINUING DATA VERIFIED:

** FOREIGN APPLICATIONS VERIFIED:

JAPAN 2000-400814 12/28/2000

PG-PUB DO NOT PUBLISH ☐

RESCIND ☐

Foreign priority claimed ☐ yes ☐ no

35 USC 119 conditions met ☐ yes ☐ no

Verified and Acknowledged Examiners's initials

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TITLE : Substrate inspection system and method for controlling same

U.S. DEPT. OF COMM./PAT & TM-PTO-436US-12-01

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claim for O.G.
Assistant Examiner		DRAWING	
		Sheets Drwg.	Figs.Drwg. Print Fig.
ISSUE FEE			
Amount Due	Date Paid		
		Primary Examiner	
		Applicati n Examiner	
<input type="checkbox"/> TERMINAL DISCLAMER		PREPARED FOR ISSUE	
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